ABSTRACT OF THE DISCLOSURE

In the typical LCD device, the ON/OFF inspection is performed by unit cell. However, in the case of the small size LCD device, since the liquid crystal cell substrate has many unit cells, the total inspection time is too long and the long handling time contributes to increasing the number of inferior cells. To solve these problems, the ON/OFF inspection of the liquid crystal cell for the small size LCD device having many unit cells is simultaneously performed for the entire liquid crystal cell substrate before cutting into the unit cells. Thus, the number of damaged cells during the inspection process and the process time can be reduced, and the yield can increase.